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Tunnelling effects and electron transport in quantum dot structures

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Abstract

Using an analytical model of electron confinement in quantum dots, we have calculated the tunnelling rates for electron quasi-bound states. Schrödinger equation for the disk-shaped system in consideration is readily solved both in the time-dependent and time-independent versions, and the quantitative importance of tunnelling phenomena in low temperature electron emission from quantum dots is revealed. Results of the quantum mechanical analysis are transferred into the device characteristics of common multi-layer quantum dot hetero-structures.

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1. Introduction

It is generally recognized that the properties of multi-layer quantum dot (QD) devices, such as photodetectors, critically depend on the number N of electrons occupying the QD, and the electron capture/emission rates. This is because the electric current under applied voltage, $j \sim e\Sigma_{\rm QD}/pG$, is proportional to the electron escape rate, G = G(N) (due to photo-induced, thermionic or any other mechanism), density of QDs, Σ , and inversely proportional to the electron capture probability, p = p(N).

The thermal dark current and photocurrent in QD structures have been studied in detail previously [1]. However, for the calculations of the dark current characteristics at low temperatures, the explicit dependence of the electron tunnelling escape rate on N and other parameters is indispensable. Specific features of QDs studied in the recent experiments are low QD density Σ_{QD} and a flattened shape. This provides the possibility of spontaneous electron tunnelling in the lateral directions when QDs are markedly charged.

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2. Model quantum dot

Let us review a typical QD in hetero-structures considered above. The important QD parameters are especially (i) the lateral radius, *a*, (ii) the thickness of QD, *l*, (iii) the confinement potential V_{QD} (conduction band offset), (iv) dielectric constants, κ , κ_{QD} , (v) electron masses μ , μ_{QD} , and (vi) the total confined charge *N*. The 2D axially symmetric hamiltonian is

$$\hat{H} = -\frac{\hbar^2}{2\mu_i} \left[\frac{\partial^2}{\partial r^2} + \frac{1}{r} \frac{\partial}{\partial r} - \frac{m^2}{r^2} + \frac{\partial^2}{\partial z^2} \right] + V(r, z), \qquad (1)$$

where *m* is the azimuthal quantum number. Let us invoke the flat disk quantum dots, assuming only one quantum level in the *z*-direction, $l_{\text{QD}} \ll a$. Supposing further a QD with a number of electrons (thus closer to a uniform charge distribution), the *z*-dimension may be reduced out, and the potential function $V(r,z) \simeq V(r)$ includes both the QD attraction and electrostatic repulsion,

$$V(r) \simeq \begin{cases} -V_{\rm QD} \text{ for } r \leq a, \text{ and otherwise:} \\ N \frac{e}{a} \left[\frac{1}{\kappa} \arctan\left(\sqrt{\frac{a^2}{r^2 - a^2}}\right) - \frac{\pi}{2\kappa_{\rm QD}} \right]. \end{cases}$$
(2)

This potential is shown in Fig. 1 for N = 16.

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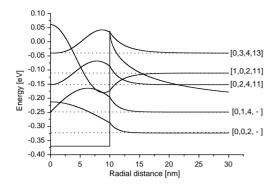


Fig. 1. Schematic view of QD. Bold line: the potential curve (N = 16, centrifugal terms excluded). Dotted lines: energy levels, thin lines: wave functions (arbitrary units). Numbers in bracket indicate: [quantum numbers n, m, maximum level occupation number, and minimal N for which tunnelling may occur].

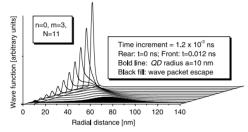


Fig. 2. Tunnelling dynamics in time.

3. Results and discussions

The *n*th bound-state wave function of single electron,

$$J_m(\sqrt{2\mu_{\rm QD}(E_n - V_{\rm QD})r/\hbar}) \quad \text{for } r \leq a, \tag{3}$$
$$H_m^{(1)}(i\sqrt{2\mu(-E_n)}r/\hbar) \quad \text{for } r \geq a, \tag{4}$$

is to be matched numerically at
$$r = a$$
. The ratio of logarith-
mic derivatives between the Bessel and Hankel functions
[2] is prescribed as μ_2/μ_1 , which yields the energy spec-
trum, $\{-|E_n|\}_n$. The electrostatic potential in Eq. (2) is a
perturbation, which effectively lowers the confinement po-
tential at large r . The energy levels $E_n > -Ne\pi/(2a\kappa_{QD})$
thus become open for tunnelling (cf. Fig. 1). The tunnelling
rates are then obtained by solving the time-dependent
Schödinger equation with the initial wave packet given by
Eq. (3), for which several time-space grid method or the
split-operator technique can be employed (see Fig. 2). We
adopt the Vischer algorithm, since it is sufficiently fast and
also unitary. Absorbing boundary condition is implemented
(i.e., a small negative imaginary part added to V at large
values of r). Invoking the well-studied InAs/GaAs QD sys-
tem, let us choose the typical QD parameters $a = 10$ nm,

Table 1 The tunnelling rates λ_k (in ns⁻¹)

N	11	12	13	14	15	16
,	0.01 72	0.20 101	1.03 131 389	2.73 162 432	5.88 195 476	11.5 222 519

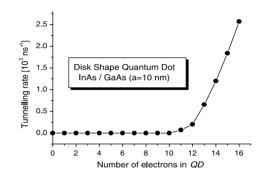


Fig. 3. Electron total tunnelling rate as a function of charge.

 $\kappa_{\rm OD} = 15.15, \ \kappa = 12.91, \ \mu_{\rm OD} = 0.027m_0, \ \mu = 0.067m_0,$ $V_{\rm QD} = 0.37$ eV and N = (0-16). Energy levels follow from Eq. (3), results are shown in Fig. 1. For each level k, the population number $0 \le v_k \le 1$ is time dependent, $v_k(t) =$ $\int_{OD} |\psi_k(r,t)^2| dr$, with $v_k(t) \simeq \exp(-\lambda k_t)$. The tunnelling rates λ_k (in ns⁻¹) are shown in Table 1. The total tunnelling rate reads $-dN(t)/dt|_{t=0} = \sum_k N_k \lambda_k$, where N_k is the number of electrons occupying the kth level. In Fig. 3, the total tunnelling rate as a function of charge N is displayed (the above InAs/GaAs QD parameters were used). The increase in the tunnelling rate with N is due to two factors, (1) increase of electron repulsion inside QD ($\sim N$), and (2) occupation of higher lying OD states closer to the barrier top. The slope change in Fig. 3 from N = 11, 12 to N = 13, ..., 16 is, e.g., due to a newly occupied level n = 0, m = 3 at $N \ge 13$ (cf. Fig. 1). Figs. 1 and 3, and the state-resolved tunnelling rate tables are the main results used in low temperature device models.

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